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# New insights into the spatiotemporal structure of plastic flow by combination of modeling and in-situ experimental techniques

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# Characterization of deformation behavior in bulk

## Universal Testing Machines, (Micro)hardness

- Stress-strain (or load-time) dependence

## Complementary “*quasi in-situ*” techniques

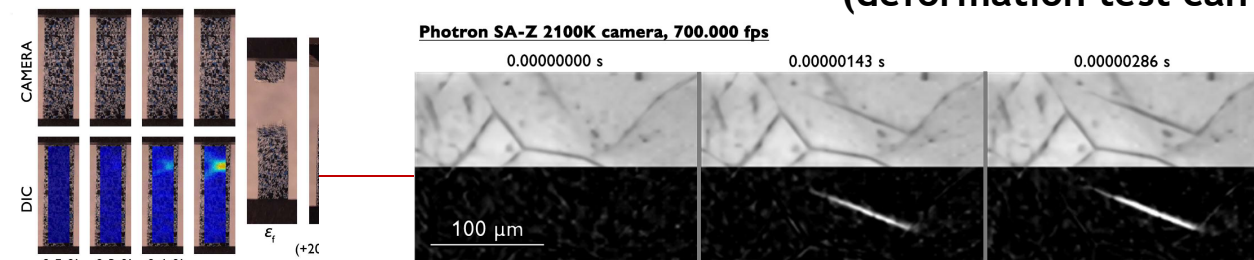
- Scanning electron microscopy (incl. EBSD)
- Diffraction methods (X-ray, neutrons, tomography)

→ **Data acquisition takes time**  
(deformation test needs to be repeatedly halted)

## Complementary *in-situ* techniques

- High-speed camera recording (incl. DIC)

→ **High data acquisition rate**  
(deformation test can run smoothly)



Knapek et al., 2022

Máthys et al., 2022, unpublished results

# Characterization of deformation behavior in **microsamples**

## Direct comparison with modeling

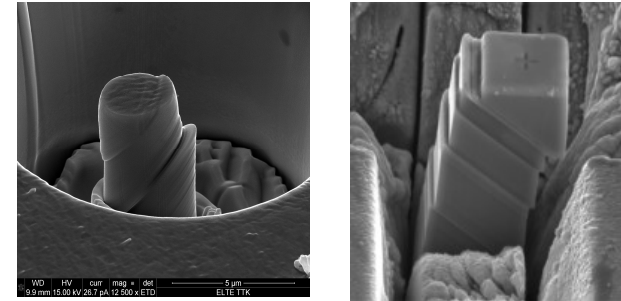
### Dedicated nanodevices

- Stress-strain (or load-time) dependence

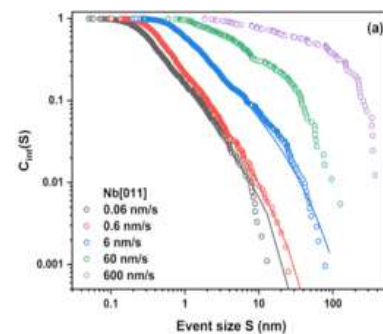
### The results are very sensitive to experimental details

- Pillar shape (tapering)
- Machine stiffness
- Deformation rate
- Stage control etc.

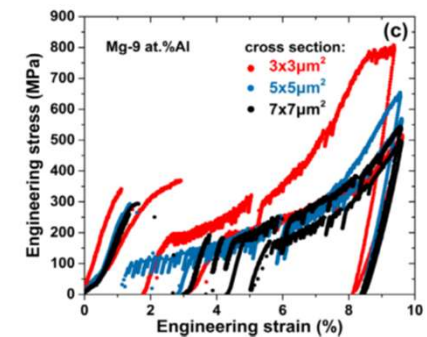
Sampling rate ~250 Hz



Á. I. Hegyi *et al.*, *Microsc. Microanal.*, 2017



Sparks and Maaß, *PR Materials*, 2018



J. Wang *et al.*, *Acta Mater.*, 2020

# Characterization of deformation behavior in **microsamples**

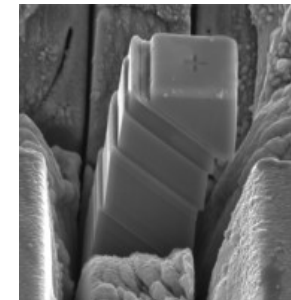
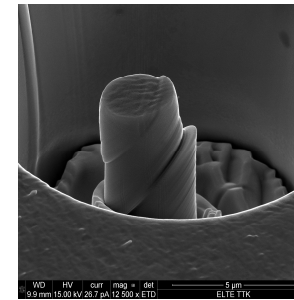
## Direct comparison with modeling

Dedicated nanodevices - sampling rate ~250 Hz

- Stress-strain (or load-time) dependence

Complementary **high spatial resolution** techniques

- Scanning electron microscopy (incl. EBSD)
- Transmission electron microscopy



Á. I. Hegyi *et al.*, *Micros. Microanal.*, 2017

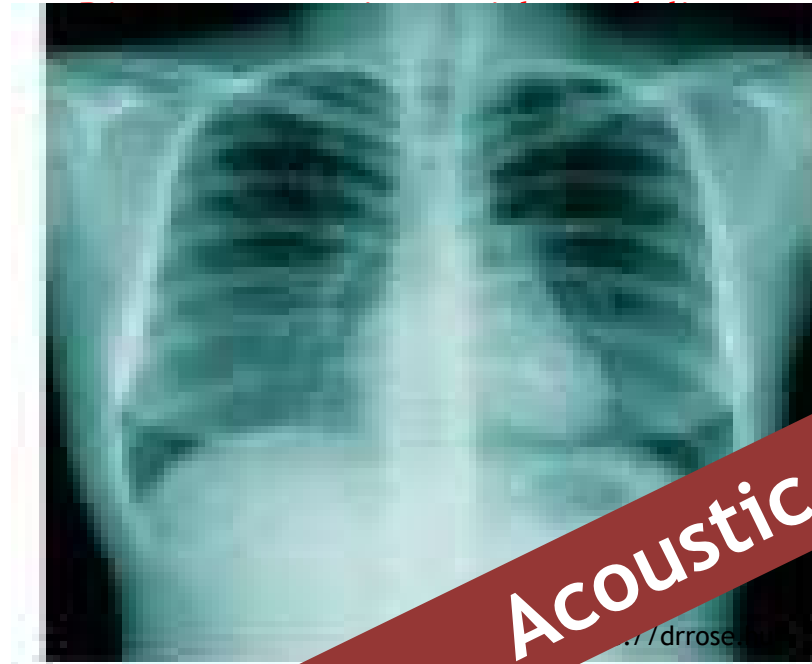
→ **Low sampling rate**  
~ 1-2 Hz

Complementary **high temporal resolution** techniques

- High-speed camera recording

→ either **low image resolution**  
~ 128 x 32 px @ 2.1M FPS  
or **short acquisition time**  
~ 100  $\mu$ s @ 5M FPS

# Characterization of deformation behavior in micropillars



250 Hz

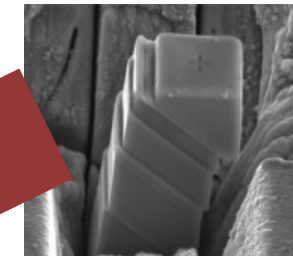
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Acoustic emission (AE)



shutterstock.com · 2074183925

# Characterization of deformation behavior in micropillars

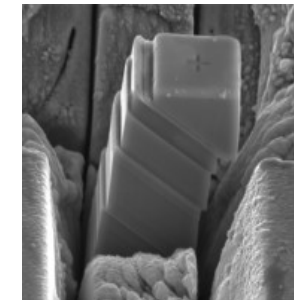
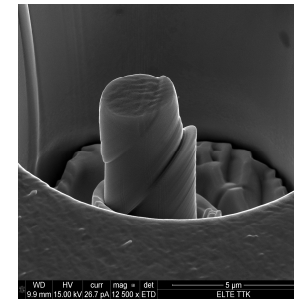
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Á. I. Hegyi *et al.*, *Micros. Microanal.*, 2017

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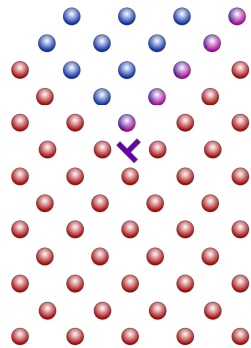
Complementary **high temporal resolution** techniques

- High-speed camera recording
- **ACOUSTIC EMISSION** - sampling rate up to 40 MHz

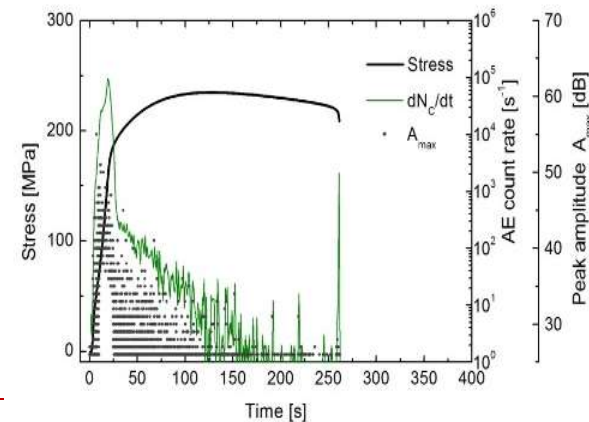
→ either **low image resolution**  
~ 128 x 32 px @ 2.1M FPS  
or **short acquisition time**  
~ 100  $\mu$ s @ 5M FPS

# Introduction to the acoustic emission (AE)

- ASTM E610-82: Acoustic emissions are transient elastic waves generated by the rapid release of energy from localized sources within the material.
- AE is sound of danger in the nature (earthquakes, rockbursts, avalanches)
- AE in materials - information on the dynamic processes involved in plastic deformation and failure (**collective dislocation motion, twinning, crack propagation etc.**)

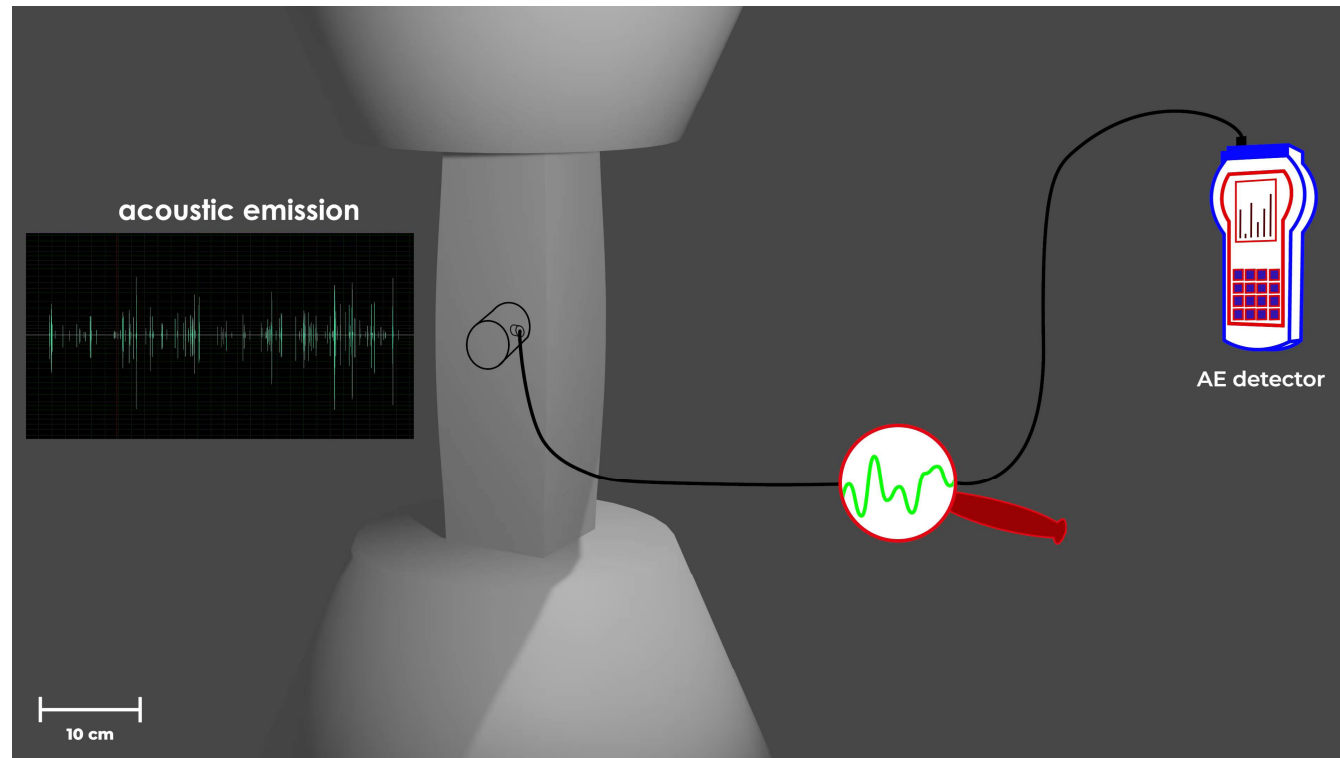


<https://www.youtube.com/watch?v=HoRvTnsiaE8&t=85s>



D. Drozdenko et al., Acta Phys. Pol., A, 2015

## Basic principles of the AE measurements



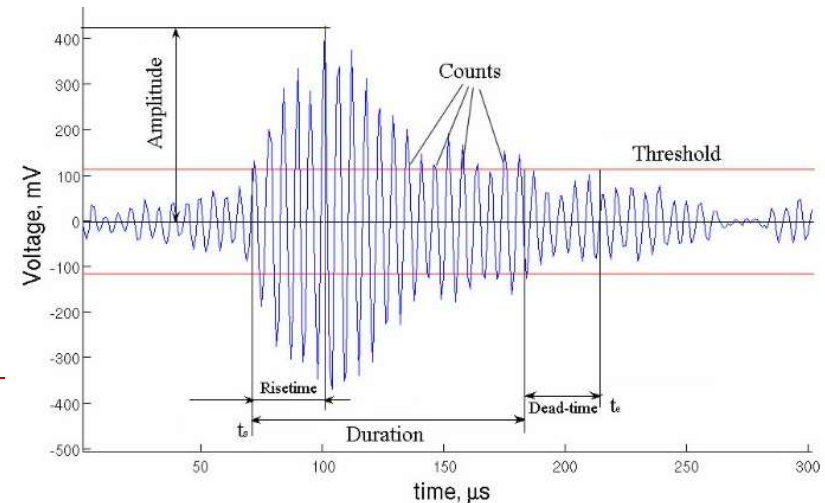
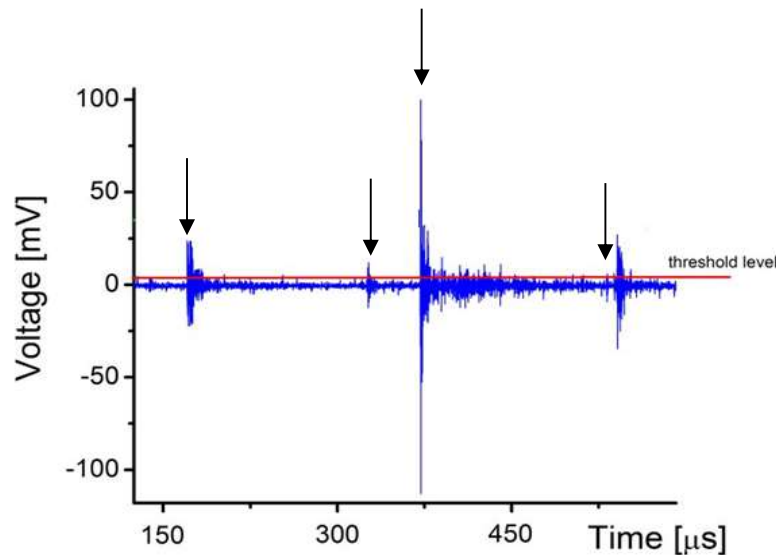
<https://www.youtube.com/watch?v=HoRvTnsiaE8&t=85s>



# Basic principles of the AE measurements

## Hit-based method

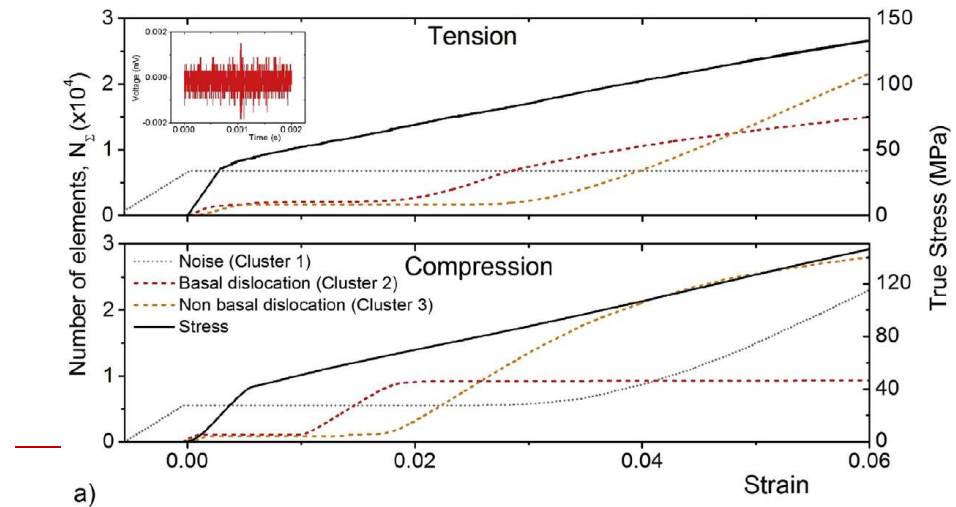
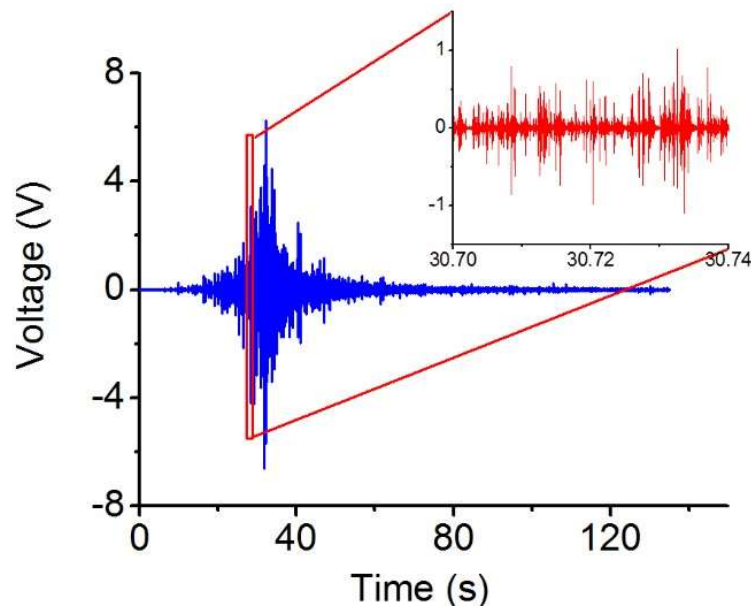
- Threshold level - exclusion of the background noise
- Recording of an AE hit starts, when signal cross first the threshold level and terminates, if signal is below threshold for hit-definition-time (dead time)
- The results are sensitive on proper (pre-experiment) choice of threshold and HDT



# Basic principles of the AE measurements

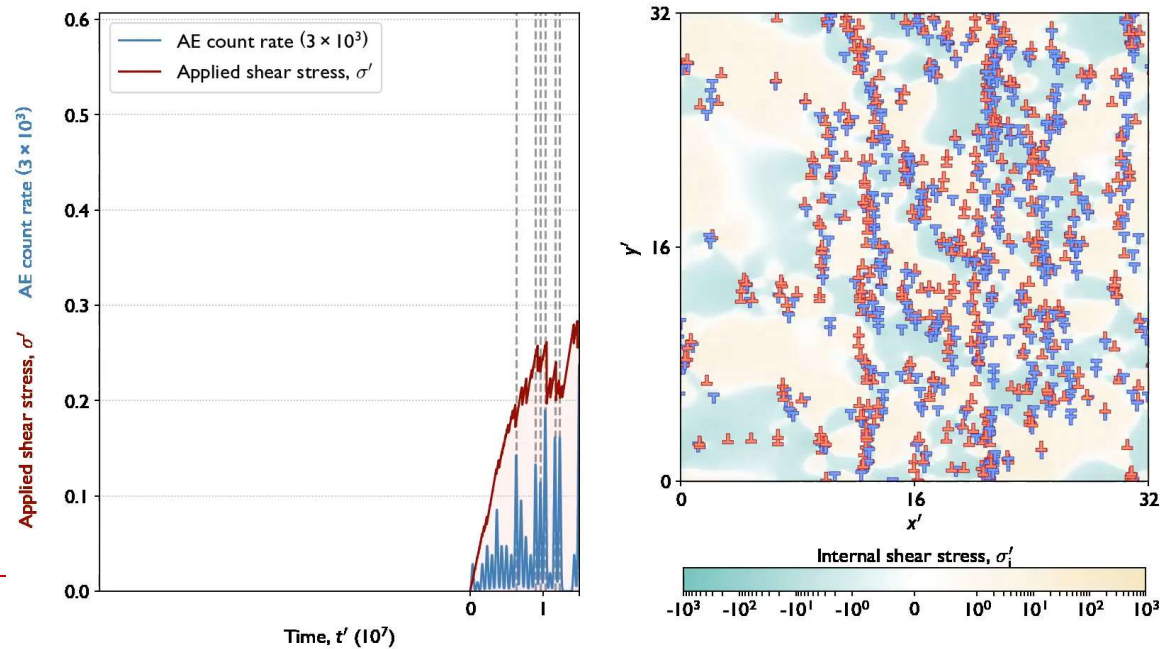
## Data streaming

- Continuous sampling and storing of the signal - **acquisition rate up to 40 MHz**
- AE parameters from post-processing - no data loss, better fit of set-up parameters
- Getting **dynamic information** about the plastic deformation



# AE and dislocation movement

- Scruby et al. (1981) - single dislocation: surface displacement of  $10^{-15}$  m, detectable by AE:  $>10^{-13}$  m.  $\Rightarrow$  AE sensitive to collective correlated movement of large dislocation ensembles (dislocation avalanches);



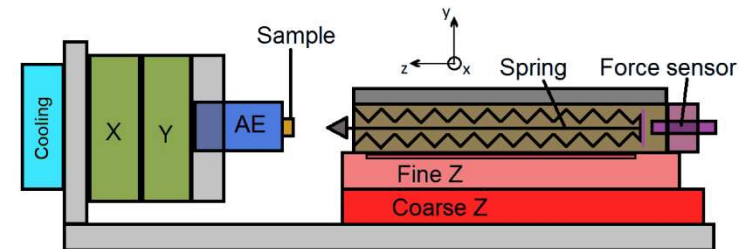
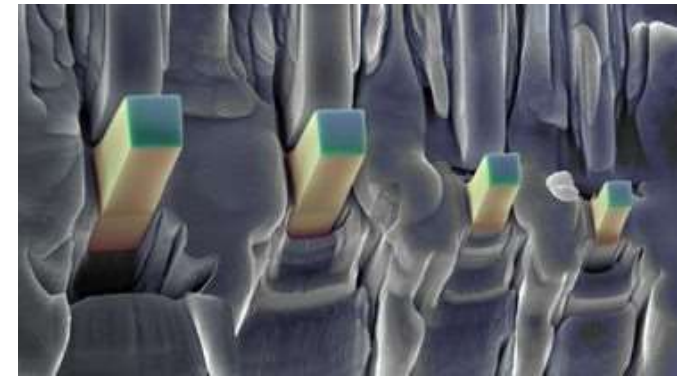
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- Experimental evidence of intermittent character of PD - **AE signals during mechanical loading of materials**. [M.-C. Miguel et al., *Nature*, 410(6829), 667-671, 2001; J. Weiss et al., *Science*, 299(5603), 89-92, 2003]
- Up to now, **deformation and AE experiments only on macroscopic samples** (mono-, poly-crystals).
- **QUESTION: Can AE be employed to investigate plasticity in microsamples?**

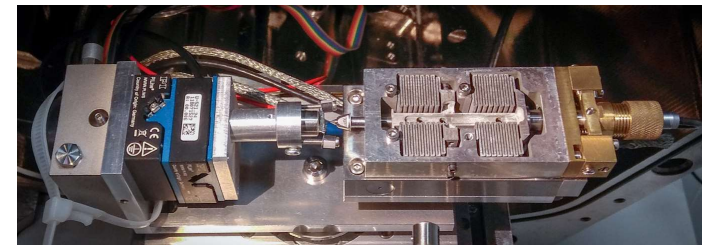
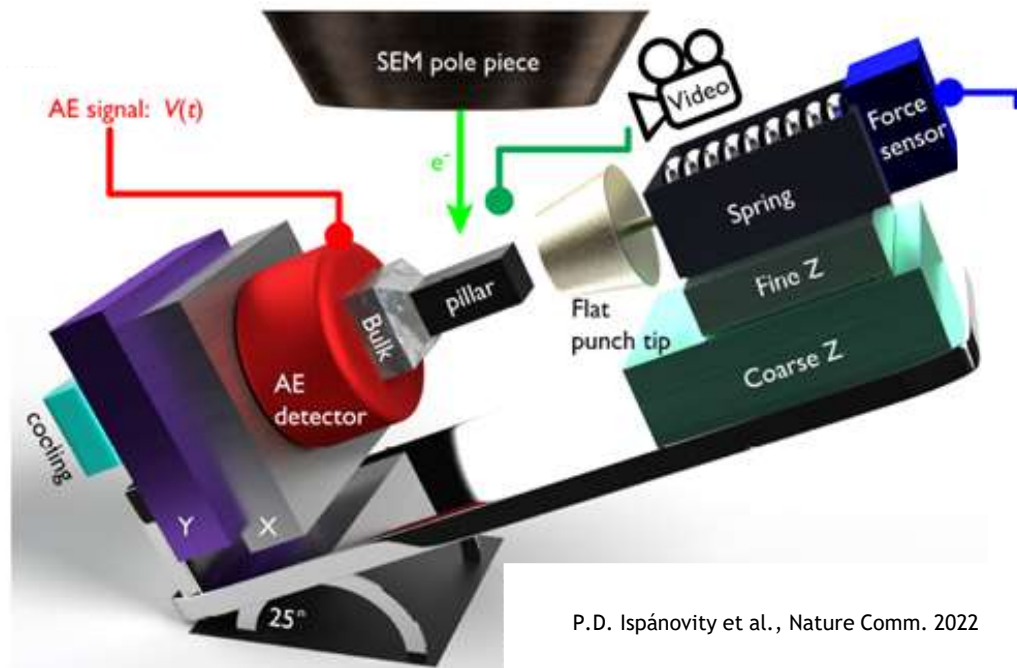
## Plastic deformation in microsamples

- FIB - focused ion beam - new production method was developed: rectangular micropillars (non-tapered, faster production, ...).
- In-situ micromechanical device “Nanotest” and AE transducer placed directly in SEM (FEI Quanta 3D).
- Sample attached to the sensor (metallic strip + vacuum grease).
- Deformation test - flat diamond tip.
- AE: Vallen Systeme GmbH AE system and preamplifier + Physical Acoustic Corp. sensor.



[Á. Hegyi, et al., *Microsc. Microanal.* 23(6), 1076–1081, 2017]

# Plastic deformation in microsamples

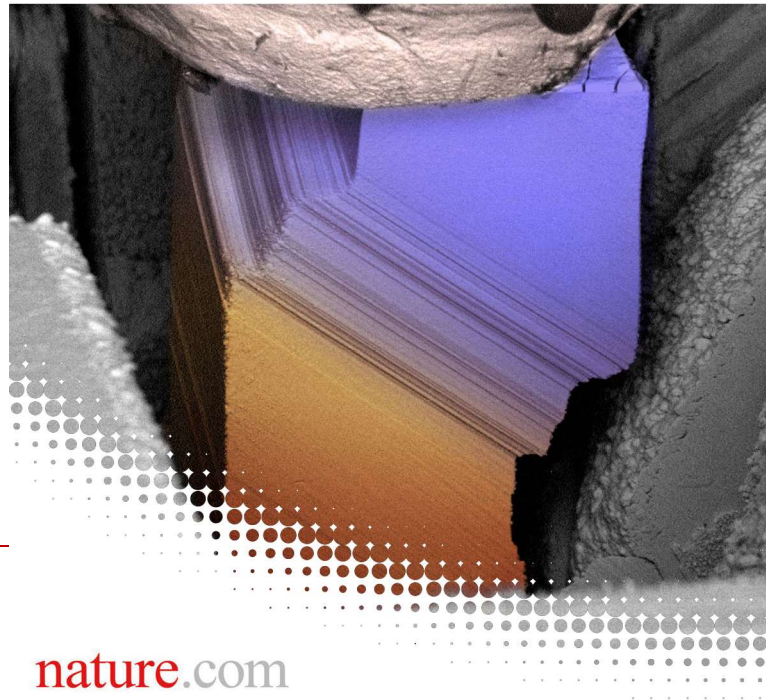


Part name	Total range	Resolution	Accuracy
X and Y stages	$\pm 8$ mm	$0.5 \mu\text{m}$	$0.01 \mu\text{m}$
Coarse Z stage	9 mm	$2 \mu\text{m}$	$0.5 \mu\text{m}$
Fine Z stage	$35 \mu\text{m}$	1 nm	0.1 nm
Force sensor (with two possible presets)	20/50 mN	$1/2.5 \mu\text{N}$	$1/2.5 \mu\text{N}$

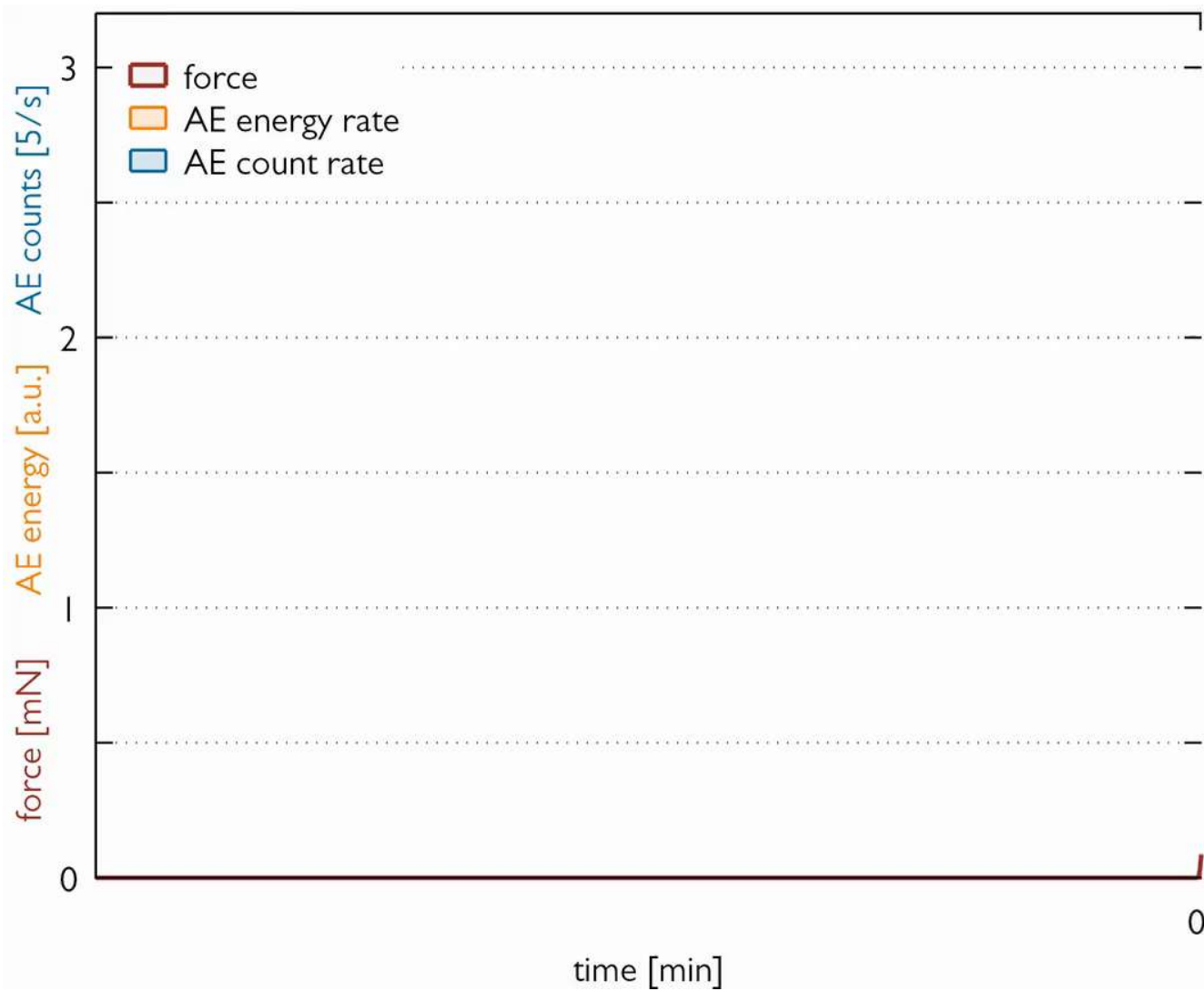


P. D. Ispánovity\*, D. Ugi\*, G. Péterffy, M. Knapek, S. Kalácska, D. Tüzes,  
Z. Dankházi, K. Máthis, F. Chmelík, I. Groma  
**Dislocation avalanches are like earthquakes on the micron scale**  
2022

<https://doi.org/10.1038/s41467-022-29044-7>

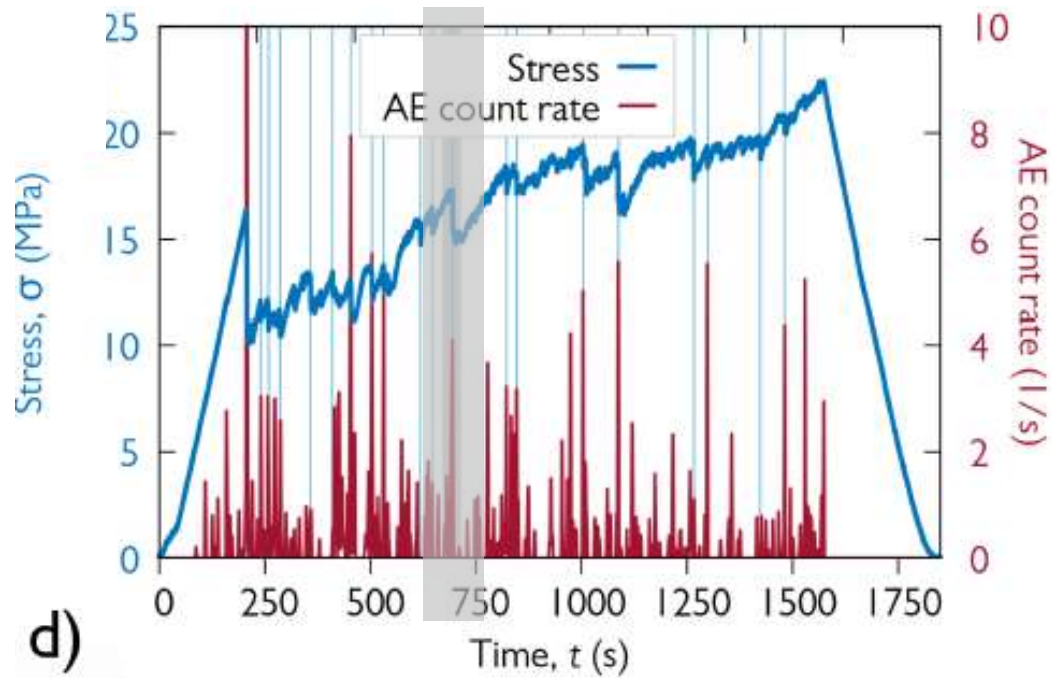


[nature.com](https://www.nature.com)



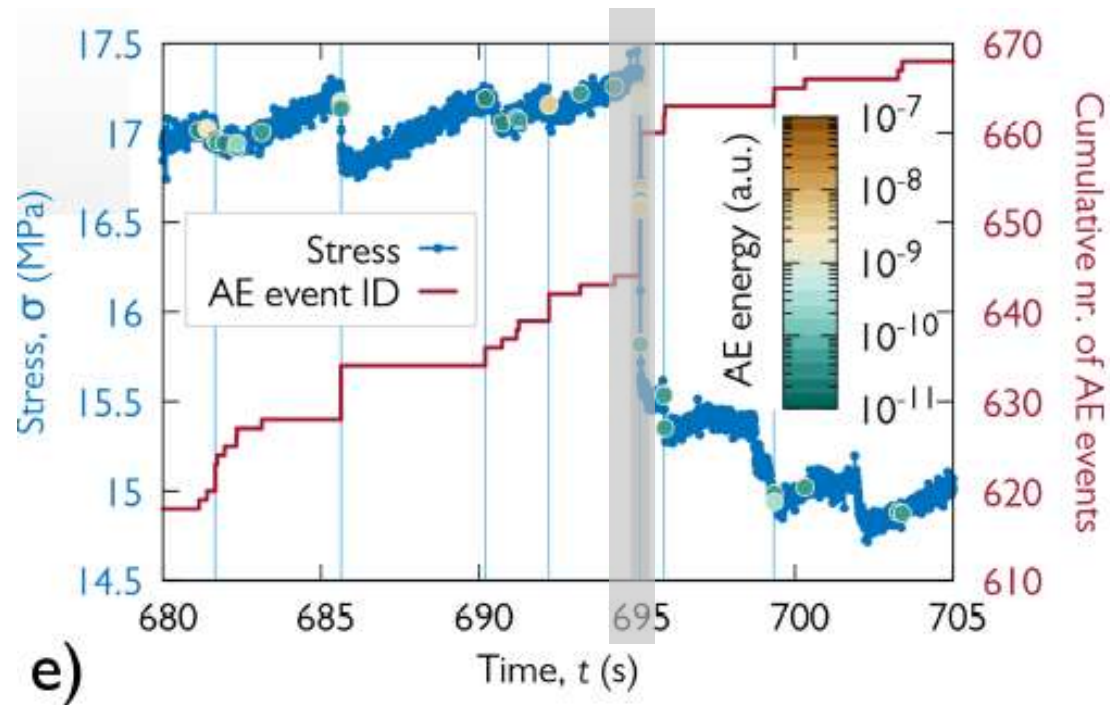


## Zn micropillars oriented for single slip



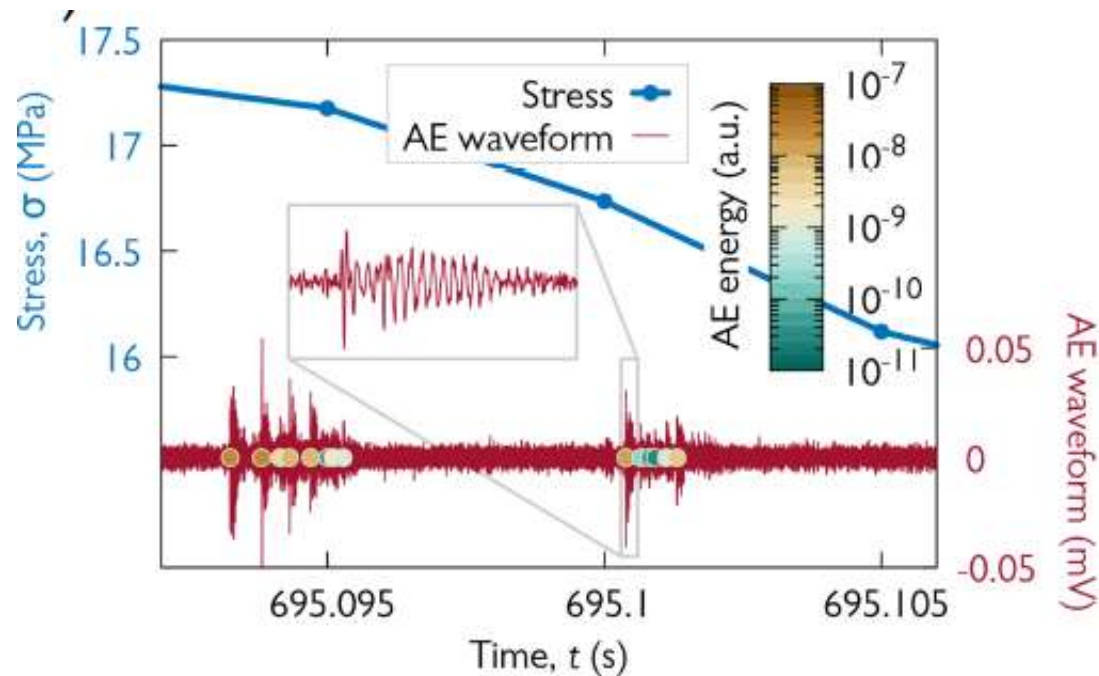
- Correlation between stress drops and AE

## Zn micropillars oriented for single slip



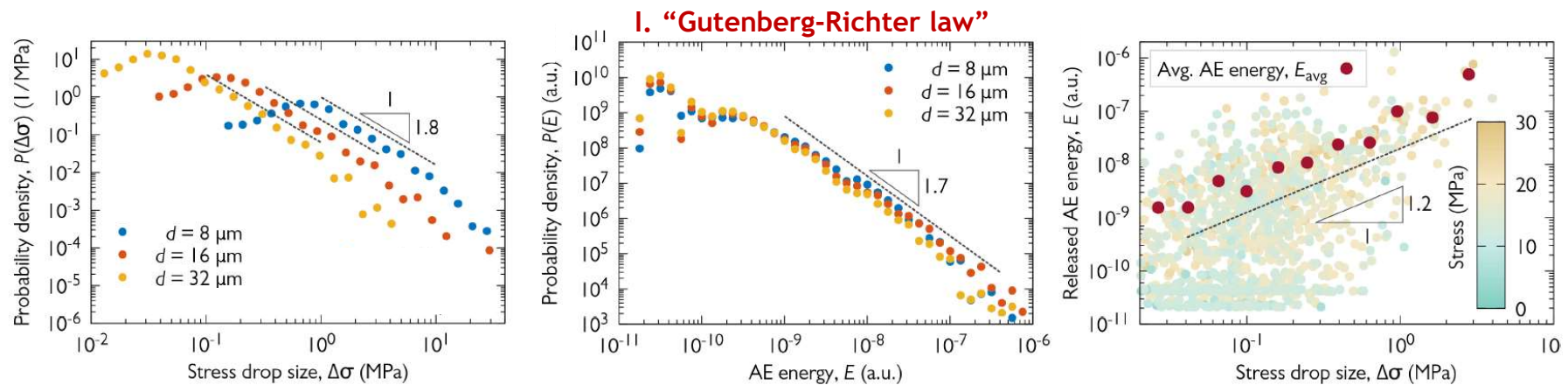
- Correlation between stress drops and AE
- Several AE events during a drop

## Zn micropillars oriented for single slip



- Correlation between stress drops and AE
- Several AE events during a drop
- Single stress drop is a result of complex internal dynamics on timescales not accessible by stress measurements

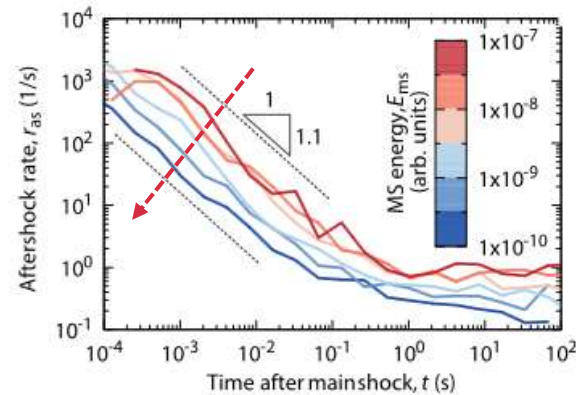
# Dislocation slip statistics vs. earthquakes dynamics



- Power-law behavior of the released energy
- A physical relation between the particular stress drops and the corresponding AE energies

# Dislocation slip statistics vs. earthquakes dynamics

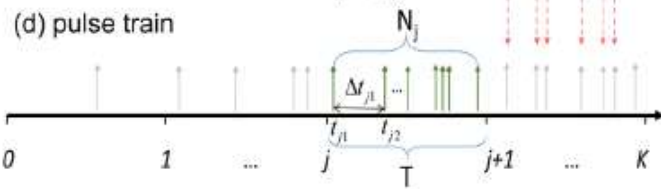
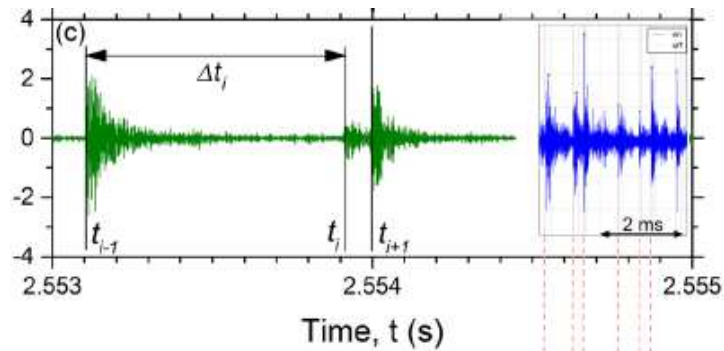
## II. “Omori law” & III. “Productivity law”



- **Omori-law:**  
 $n(t) \sim 1/t$  ( $n$  - # of aftershocks/time unit;  $t$  - time elapsed after main shock)
- **Productivity-law:**  
main shocks with larger energy produce on average more aftershocks

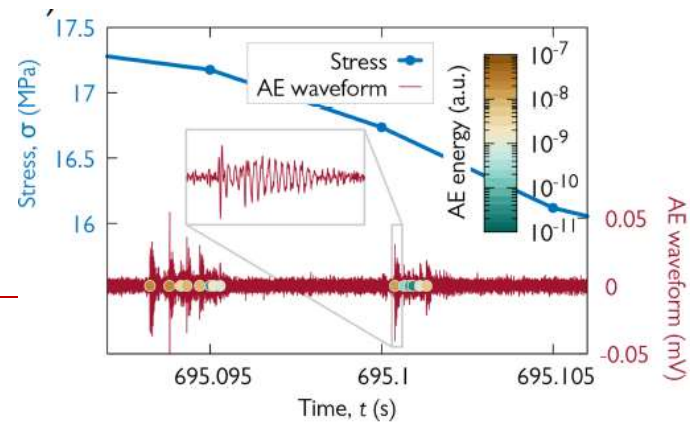
**Statistical features of Zn micropillars resemble dynamics of earthquakes**

# Clustering in temporal processes

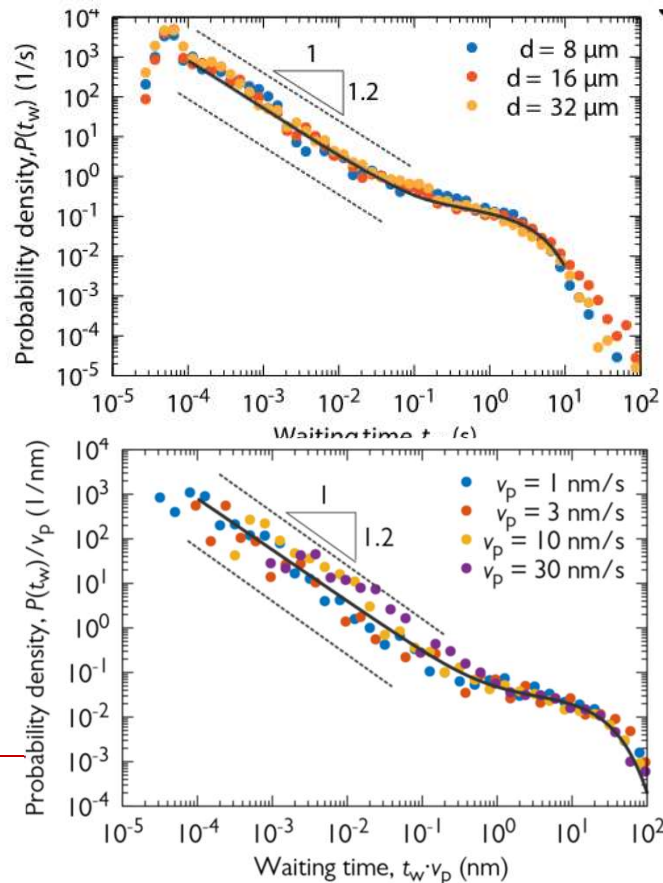


A. Vinogradov et al., Sci. Reports. 2019

- Analysis of the waiting times  $t_w$  between the subsequent events

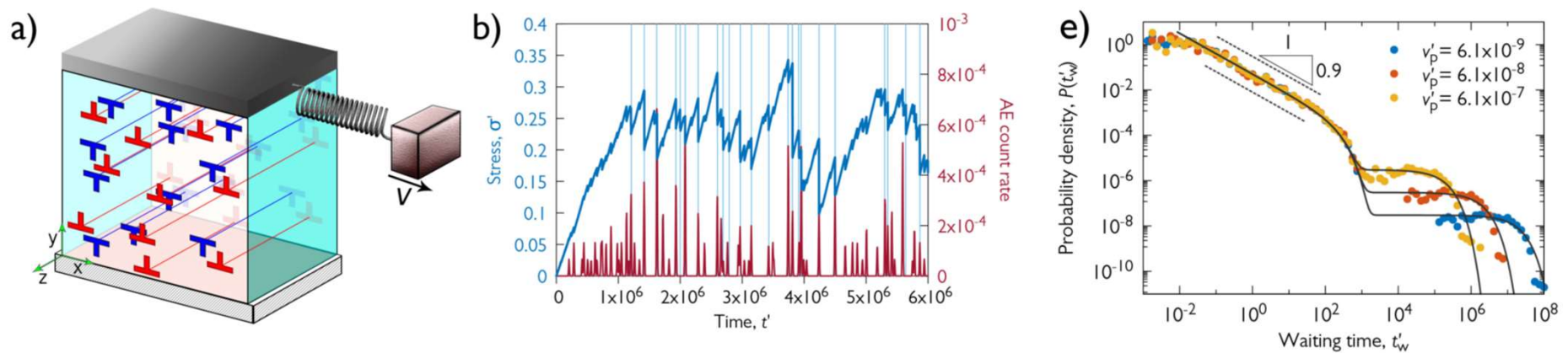


# Clustering in temporal processes



- Analysis of the waiting times  $t_w$  between the subsequent events
- Universal gamma distribution
 
$$P(t_w) = \left( A t_w^{-(1-\gamma)} + B \right) \exp\left(-\frac{t_w}{t_0}\right)$$
- **Power-law distribution for small ( $\leq 0.1 \text{ s}$ )  $t_w$ :** correlation between the events of the same stress drop
- **Plateau with exponential cut-off for larger times:** Poisson-like distribution, uncorrelated main shocks
- Negligible effect of the pillar size
- Platen velocity does not influence the single event dynamics
- In the cut-off region  $B \propto v_p$   $t_0 \propto v_p^{-1}$

# Discrete dislocation dynamics modeling



- Excellent agreement with the experiments
- The complex dynamic behavior observed in experiments is the result of the spatio-temporal correlations of the dislocations due to their long-range elastic interactions



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# Conclusions

## Experimental

- **Profound correlations are observed** between the energies of plastic and AE events, induced by the collective dissipative motion of dislocations
- **AE is a convenient high-resolution “proxy”** for elementary plastic events.

## Scientific

- The intermittency and scale-invariance characterizing plastic deformation of HCP single crystals are related to the self-organized critical (SOC) behavior of dislocations
  - The **plastic events exhibit both spatial and temporal clustering** with long-range correlations
  - Statistical analyses further show that **despite fundamental differences in deformation mechanism and involved length- and time-scales, dislocation avalanches and earthquakes are essentially alike.**
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# Thank you

*Nat. Commun.* paper:



*Youtube video:*



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- Hungarian Ministry of Human Capacities within the ELTE Institutional Excellence Program TKP2020-IKA-05 (P.D.I, D.U, G.P., D.T., Z.D. and I.G.),
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- Czech Science Foundation (grant No. 19-22604S; M.K. and F.C).